Graduate Texts in Physics

Marius Grundmann

The Physics of Semiconductors

An Introduction including Nanophysics and Applications

Second Edition

半导体物理学 第2版

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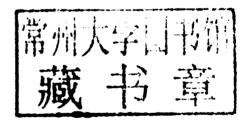
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With 247 Figures





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作 者:

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To Michelle,
Sophia Charlotte
and Isabella Rose

Preface

Semiconductor electronics is commonplace in every household. Semiconductor devices have also enabled economically reasonable fiber-based optical communication, optical storage and high-frequency amplification and have recently revolutionized photography, display technology and lighting. Along with these tremendous technological developments, semiconductors have changed the way we work, communicate, entertain and think. The technological progress of semiconductor materials and devices is evolving continuously with a large worldwide effort in human and monetary capital. For students, semiconductors offer a rich, diverse and exciting field with a great tradition and a bright future.

This book introduces students to semiconductor physics and semiconductor devices. It brings them to the point where they can specialize and enter supervised laboratory research. It is based on the two semester semiconductor physics course taught at Universität Leipzig in its Master of Science physics curriculum. Since the book can be followed with little or no pre-existing knowledge in solid-state physics and quantum mechanics, it is also suitable for undergraduate students. For the interested reader some additional topics are included in the book that can be covered in subsequent, more specialized courses. The material is selected to provide a balance between aspects of solid-state and semiconductor physics, the concepts of various semiconductor devices and modern applications in electronics and photonics.

The first semester contains the fundamentals of semiconductor physics (Part I, Sects. 1–10) and selected topics from Part II (Sects. 11–19). Besides important aspects of solid-state physics such as crystal structure, lattice vibrations and band structure, semiconductor specifics such as technologically relevant materials and their properties, electronic defects, recombination, hetero- and nanostructures are discussed. Semiconductors with electric polarization and magnetization are introduced. The emphasis is put on inorganic semiconductors, but a brief introduction to organic semiconductors is given in Sect. 16. Dielectric structures (Sect. 18) serve as mirrors, cavities and microcavities and are a vital part of many semiconductor devices. Other sections give introductions to carbon-based nanostructures and transparent conductive oxides (TCOs). The third part (Part III – Sects. 20–23) is dedicated to semiconductor applications and devices that are taught in the second semester of the course. After a general and detailed discussion of

various diode types, their applications in electrical circuits, photodetectors, solar cells, light-emitting diodes and lasers are treated. Finally, bipolar and field-effect transistors including thin film transistors are discussed.

In the present text of the second edition a few errors and misprints of the first edition have been corrected. Many topics have been extended and are treated in more depth, e.g. dopant diffusion, partial dislocations, etching of semiconductors, double donors/acceptors, excess charge carrier profiles, direct transitions in germanium, alloy broadening, nanowires, recombination in organic semiconductors, depletion layers beyond the abrupt approximation, Schottky diodes with inhomogeneous barrier, multi-junction solar cells, quantum dot and organic LEDs, LED degradation, strained channel transistors, MOSFET scaling, memory concepts and thin film transistors. The two chapters on carbon-based nanostructures and transparent conductive oxides have been added.

The number of references has been doubled with respect to the first edition. The references have been selected to (i) cover important historical and milestone papers, (ii) direct to reviews and topical books for further reading and (iii) give access to current literature and up-to-date research. In Fig. 1, the almost 1500 references in this book are shown by year. Roughly three phases of semiconductor physics and technology can be seen. Before the realization of the first transistor in 1947, only a few publications are noteworthy. Then an intense phase of understanding the physics of semiconductors and developing semiconductor technology and devices based on bulk semiconductors (mostly Ge, Si, GaAs) followed. At the end of the 1970s, a new era began with the advent of quantum wells and heterostructures, and later nanostructures (nanotubes, nanowires and quantum dots) and new materials (e.g. organic semiconductors, nitrides or graphene).

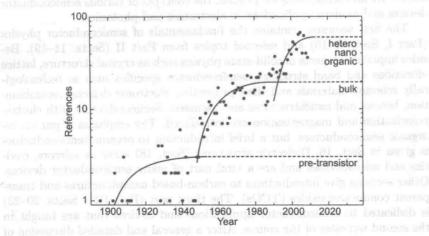


Fig. 1. Histogram of references in this book

I would like to thank several colleagues for their various contributions to this book, in alphabetical order (if no affiliation is given, from Universität Leipzig): Gabriele Benndorf, Klaus Bente, Rolf Böttcher, Matthias Brandt, Christian Czekalla, Christof Peter Dietrich, Pablo Esquinazi, Heiko Frenzel, Volker Gottschalch, Helena Hilmer, Axel Hoffmann (TU Berlin), Alois Krost (Otto-von-Guericke Universität Magdeburg), Alexander Lajn, Michael Lorenz, Thomas Nobis, Rainer Pickenhain, Hans-Joachim Queisser (Max-Planck-Institut für Festkörperforschung, Stuttgart), Bernd Rauschenbach (Leibniz-Institut für Oberflächenmodifizierung, Leipzig), Bernd Rheinländer, Heidemarie Schmidt, Mathias Schmidt, Rüdiger Schmidt-Grund, Matthias Schubert, Jan Sellmann, Oliver Stier (TU Berlin), Chris Sturm, Gerald Wagner, Holger von Wenckstern, Michael Ziese, and Gregor Zimmermann. Their comments, proof reading, experimental data and graphic material improved this work. Also, numerous helpful comments from my students on my lectures and the first edition of this book are gratefully acknowledged.

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Leipzig, April 2010

Marius Grundmann

Abbreviations

2DEG	two-dimensional electron gas	
A	atomic mass $(A = 12 \text{ for } ^{12}\text{C})$	
AAAS	American Association for the Advancement of	of Science
AB	antibonding (position)	
ac	alternating current	
ACS	American Chemical Society	
AFM	atomic force microscopy	
AIP	American Institute of Physics	
AM	air mass (2004) was blive begreen which	
APD	antiphase domain	
APD	avalanche photodiode	
APS	American Physical Society	
AR	antireflection	
ARPES	angle-resolved photoemission spectroscopy	
ASE	amplified spontaneous emission	
AVS	American Vacuum Society (The Science	
	& Technology Society)	
	dispractice lands introduction	
BC	bond center (position)	
bc	body-centered	
bcc	body-centered cubic	
BD	Blu-ray TM disc	
BEC	Bose-Einstein condensation	
BGR	band gap renormalization	
	the state of the s	
CAS	calorimetric absorption spectroscopy	
CCD	charge coupled device	
CD	compact disc	
CEO	cleaved-edge overgrowth	
CIE	Commission Internationale de l'Éclairage	
CIGS	Cu(In,Ga)Se ₂ material and burstangeria	
CIS	CuInSe ₂ material management of the control of the	
CL	cathodoluminescence	
	design of the second	

XXIII

XXIV Abbreviations

complementary metal-oxide-semiconductor **CMOS**

cvan-magenta-vellow (color system) CMY

CNT carbon nanotube

COD catastrophical optical damage

central processing unit CPU cathode ray tube CRT coincident site lattice CSL CVD chemical vapor deposition

continuous wave cw CZCzochralski (growth)

DAP donor-acceptor pair

DBR. distributed Bragg reflector

direct current dc

distributed feedback DFB double heterostructure DH(S)

deep level transient spectroscopy DLTS DMS diluted magnetic semiconductor density of states

DOS

diode-pumped solid-state (laser) DPSS DRAM dynamic random access memory

digital versatile disc deal of the design and a second DVD

EBL electron blocking layer

electrically erasable programmable read-only memory **EEPROM**

electron-hole liquid EHL electron injection layer EIL electroluminescence EL

epitaxial lateral overgrowth ELO EMA effective mass approximation

emission layer EML

excimer laser annealing ELA

electron paramagnetic resonance EPR.

electron spin resonance ESR

erasable programmable read-only memory **EPROM**

ESF extrinsic stacking fault electron transport layer ETL

extended X-ray absorption fine structure EXAFS

2,3,5,6-tetrafluoro-7,7,8,8-tetracyano-quinodimethane F4-TCNQ

face-centered fc

face-centered cubic fcc

FeRAM ferroelectric random access memory

field-effect transistor FET

FIR far infrared

FKO	Franz-Keldysh oscillation should are be a second	
FLG	few layer graphene	
FPA	focal plane array	
FQHE	fractional quantum Hall effect	
FWHM	full width at half-maximum	
FZ	float-zone (growth)	
	liquid mongentules (somewhat property	
Gb	Gigabit should sportform the	
GIZO	GaInZnO	
GLAD	glancing-angle deposition	
GRINSCH	graded-index separate confinement heterostructure	
GSMBE	gas-source molecular beam epitaxy	
GST	Ge ₂ Sb ₂ Te ₅	
HBL	hole blocking layer	
HBT	heterobipolar transistor	
hcp	hexagonally close packed	
HCSEL	horizontal cavity surface-emitting laser	
HEMT	high electron mobility transistor	
HIGFET	heterojunction insulating gate FET	
HIL	hole injection layer	
HJFET	and the second s	
hh	heavy hole	
HOPG	highly ordered pyrolithic graphite	
HOMO	highest occupied molecular orbital	
HR	high reflection	
HRTEM	high-resolution transmission electron microscopy	
HTL	hole transport layer	
HWHM	half-width at half-maximum	
IC	integrated circuit	
IDB	inversion domain boundary	
IEEE	Institute of Electrical and Electronics Engineers ¹	
IF	intermediate frequency	
IPAP	Institute of Pure and Applied Physics, Tokyo	
IQHE	integral quantum Hall effect	
IR	infrared that is entirely the state of the s	
ISF	intrinsic stacking fault	
ITO	indium tin oxide The protospp abiliform	
JDOS	joint density of states	
JFET	junction field-effect transistor	
	aplanting of the last	
KKR	Kramers-Kronig relation	

¹Pronounced Eye-triple-E

XXVI Abbreviations

KOH potassium hydroxide KTP KTiOPO₄ material

LA longitudinal acoustic (phonon)

LCD liquid crystal display

LDA local density approximation

LEC liquid encapsulated Czochralski (growth)

LED light-emitting diode

lh light hole

LO longitudinal optical (phonon), local oscillator

LPE liquid phase epitaxy

LPCVD low-pressure chemical vapor deposition
LPP longitudinal phonon plasmon (mode)
LST Lyddane–Sachs–Teller (relation)

LT low temperature

LUMO lowest unoccupied molecular orbital

LVM local vibrational mode

MBE molecular beam epitaxy

MEMS micro-electro-mechanical system

MESFET metal-semiconductor field-effect transistor

MIGS midgap (surface) states

MILC metal-induced lateral crystallization
MIOS metal-insulator-oxide-semiconductor

MIR mid-infrared

MIS metal-insulator-semiconductor

MHEMT metamorphic HEMT

ML monolayer MLC multi-level cell

MMIC millimeter-wave integrated circuit

MO master oscillator

MODFET modulation-doped FET

MOMBE metalorganic molecular beam epitaxy
MOPA master oscillator power amplifier
MOS metal-oxide-semiconductor

MOS metal-oxide-semiconductor

MOSFET metal-oxide-semiconductor field-effect transistor

MOVPE metalorganic chemical vapor deposition

MQW multiple quantum well

MRAM magnetic random access memory
MRS Materials Research Society
MS metal—semiconductor (diode)
MSA mobility spectral analysis

MSA mobility spectral analysis

MSM metal-semiconductor-metal (diode)

MTJ magneto-tunneling junction
MWNT multi-walled (carbon) nanotube

On the second se	NDR	×	negative differential resistance	
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NEP noise equivalent power

NIR near infrared

NMOS n-channel metal-oxide-semiconductor (transistor)

NTSC national television standard colors

OLED organic light emitting diode
OMC organic molecular crystals

ONO oxide/nitride/oxide

OPSL optically pumped semiconductor laser

PA power amplifier
PBG photonic band gap
pc primitive cubic
PCM phase change memory

PFM piezoresponse force microscopy

PHEMT pseudomorphic HEMT
PL photoluminescence
PLD pulsed laser deposition

PLE photoluminescence excitation (spectroscopy)

PMC programmable metallization cell

PMMA poly-methyl methacrylate

PMOS p-channel metal—oxide—semiconductor (transistor)

PPC persistent photoconductivity
PPLN periodically poled lithium niobate

PV photovoltaic

PWM pulsewidth modulation PZT Pb $Ti_xZr_{1-x}O_3$ material

QCL quantum cascade laser

QCSE quantum confined Stark effect

QD quantum dot

QHE quantum Hall effect

QW quantum well

QWIP quantum-well intersubband photodetector

QWR quantum wire

RAM random access memory

RAS reflection anisotropy spectroscopy

RF radio frequency

RFID radio frequency identification RGB red-green-blue (color system)

RHEED reflection high-energy electron diffraction

RIE reactive ion etching

XXVIII Abbreviations

RKKY Ruderman-Kittel-Kasuya-Yoshida (interaction)

rms root mean square ROM read-only memory

RRAM resistance random access memory

SAGB small-angle grain boundary

SAM separate absorption and amplification (structure)

sc simple cubic

SCH separate confinement heterostructure SdH Shubnikov-de Haas (oscillation)

SEL surface-emitting laser

SEM scanning electron microscopy

SET single-electron transistor, single electron tunneling

SGDBR sampled grating distributed Bragg reflector

SHG second-harmonic generation

si semi-insulating

SIA Semiconductor Industry Association SIMS secondary ion mass spectrometry

SL superlattice
SLC single-level cell
SLG single layer graph

SLG single layer graphene s-o spin-orbit (or split-off)

SOA semiconductor optical amplifier SPD spectral power distribution

SPIE International Society for Optical Engineering

SPS short-period superlattice

sRGB standard RGB

SRH Shockley-Read-Hall (kinetics)
SSR side-mode suppression ratio
STM scanning tunneling microscopy
SWNT single-walled (carbon) nanotube

TA transverse acoustic (phonon)
TAS thermal admittance spectroscopy
TCO transparent conductive oxide
TE transverse electric (polarization)
TED transferred electron device

TFET transparent FET, tunneling FET

TFT thin film transistor

TEGFET two-dimensional electron gas FET transmission electron microscopy

TES two-electron satellite
TF thermionic field emission
TFT thin-film transistor

TM transverse magnetic (polarization)

TMAH tetramethyl-ammonium-hydroxide

TMR tunnel-magnetoresistance TO transverse optical (phonon)

TOD turn-on delay (time)
TPA two-photon absorption

TSO transparent semiconducting oxide

UHV ultrahigh vacuum

UV ultraviolet

VCA virtual crystal approximation VCO voltage-controlled oscillator

VCSEL vertical-cavity surface-emitting laser

VFF valence force field

VGF vertical gradient freeze (growth)

VIS visible

VLSI very large scale integration

WGM whispering gallery mode

WKB Wentzel-Kramer-Brillouin (approximation or method)

WS Wigner-Seitz (cell)

YSZ Yttria-stabilized zirconia (ZrO₂)

X exciton XX biexciton

XSTM cross-sectional STM

Z atomic number (Z = 2 for helium)

ZnPc zinc-phthalocyanine